

**Search Notes**

Application/Control No.

10/564,545

Examiner

LAN VINH

Applicant(s)/Patent under  
Reexamination

SPITZ ET AL.

Art Unit

1713

**SEARCHED**

Class	Subclass	Date	Examiner
216	2,17,18,39	6/15/2010	LV
156	345.17;	6/15/2010	LV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
key word search (USPAT,USPGPUB,USOCR,JPO,EP O,DERWENT,IBM) in EAST , inventor search	6/15/2010	LV